Applicant: Shunpei Yamazaki, et al. Attorney's Docket No.: 07977-287001 / US5276

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Amendments to the Claims:

This listing of claims replaces all prior versions and listings of claims in the application:

Listing of Claims:

1-8. (withdrawn)

9. (currently amended) A film formation method comprising the steps of: setting different temperatures to a material plural times in an evaporation source comprising the material to purify the form a purified material by sublimation stepwise; and forming a thin film on a substrate using the purified material immediately after the setting step.

10. (currently amended) A The film formation method according to claim 9, wherein the material is an EL material.

11-21. (withdrawn)

22. (original) A film formation method comprising the steps of:
evaporating a material in a first system controlled to a first temperature;
controlling a second system to a second temperature to change the material into a first gas and a first solid;

removing the first gas;

evaporating the first solid in the second system controlled to the first temperature; controlling a third system to a third temperature to change the evaporated first solid into a second gas and a second solid; and

forming a thin film using the second gas over a substrate.

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23. (currently amended) A film formation method comprising the steps of:
evaporating a material in a first system controlled to a first temperature;
controlling a second system to a second temperature to change the material into a gas and a solid;

removing the gas; and

evaporating the solid <u>to form an evaporation</u> in the second system controlled to the first temperature; <u>and</u>

forming a thin film on a substrate using the evaporation immediately after the second evaporating step.

24. (currently amended) A film formation method comprising the steps of:
evaporating a material in a first system controlled to a first temperature;
controlling a second system to a second temperature to change the material into a gas and a solid; and

forming a thin film using the gas over a substrate immediately after the controlling step.

- 25. (currently amended) A <u>The</u> film formation method according to claim 22, wherein the material is an EL material.
- 26. (currently amended) A <u>The</u> film formation method according to claim 23, wherein the material is an EL material.
- 27. (currently amended) A <u>The</u> film formation method according to claim 24, wherein the material is an EL material.
 - 28. (previously presented) A film formation method comprising the steps of: evaporating a solid including an EL material to form a gas including the EL material;

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moving the gas including the EL material with a carrier gas, and a temperature of the gas including the EL material gradually decrease in accordance with the moving;

precipitating the EL material in one position to form a precipitated EL material; and forming a thin film using the precipitated EL material.

- 29. (currently amended) A <u>The</u> film formation method according to claim 28, wherein the carrier gas is one of nitrogen and a noble gas.
- 30. (currently amended) A <u>The</u> film formation method according to claim 28, wherein the moving step is conducted in a reduced pressure state.
- 31. (previously presented) A film formation method comprising the steps of: evaporating a solid including an EL material to form a gas including the EL material in a first chamber;

moving the gas including the EL material with a carrier gas in a second chamber, and a temperature of the gas including the EL material gradually decrease in accordance with the moving;

precipitating the EL material in one position to form a precipitated EL material in the second chamber; and

forming a thin film using the precipitated EL material in a third chamber.

- 32. (currently amended) A <u>The</u> film formation method according to claim 31, wherein the carrier gas is one of nitrogen and a noble gas.
- 33. (currently amended) A <u>The</u> film formation method according to claim 31, wherein the moving step is conducted in a reduced pressure state.